

Supporting Information

Table S1. Summary of XPS Peak Analysis on NSOMC materials.

Samples	Species	NSOMC-650			NSOMC-800			NSOMC-950		
		B.E. (eV)	Rel. int. ^a (%)	Conc. (at. %)	B.E. (eV)	Rel. int. ^a (%)	Conc. (at. %)	B.E. (eV)	Rel. int. ^a (%)	Conc. (at. %)
C1s	C1	284.6	52.4		284.6	39.7		284.6	34.3	
	C2	285.3	21.7	85.0	285.4	45.0	86.3	285.4	52.7	87.9
	C3	286.2	18.8		286.5	10.3		286.9	4.3	
	C4	288.8	7.1		289.7	5.1		289.2	8.7	
N1s	N1	400.6	75.8	10.0	400.8	88.9	7.4	400.9	95.2	4.8
	N2	398.4	24.1		398.3	11.1		398.4	4.8	
S2p	S1	163.9	21.4		163.6	23.9		163.8	30.6	
	S2	164.7	22.2	0.69	164.7	25.3	0.81	164.7	8.1	0.92
	S3	165.6	4.6		165.4	35.4		165.3	7.7	
	S4	167.7	51.8		167.8	15.3		167.9	53.6	

^a Rel. int. denotes the relative intensity of the dopant species.

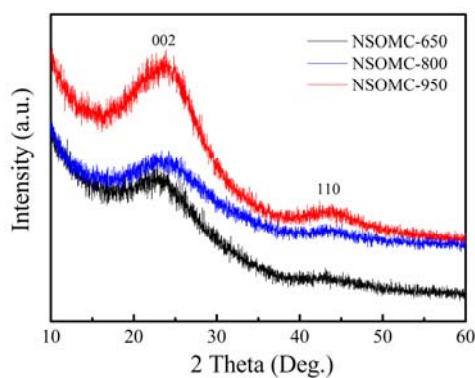


Figure S1. Wide-angle XRD patterns of NSOMC materials.

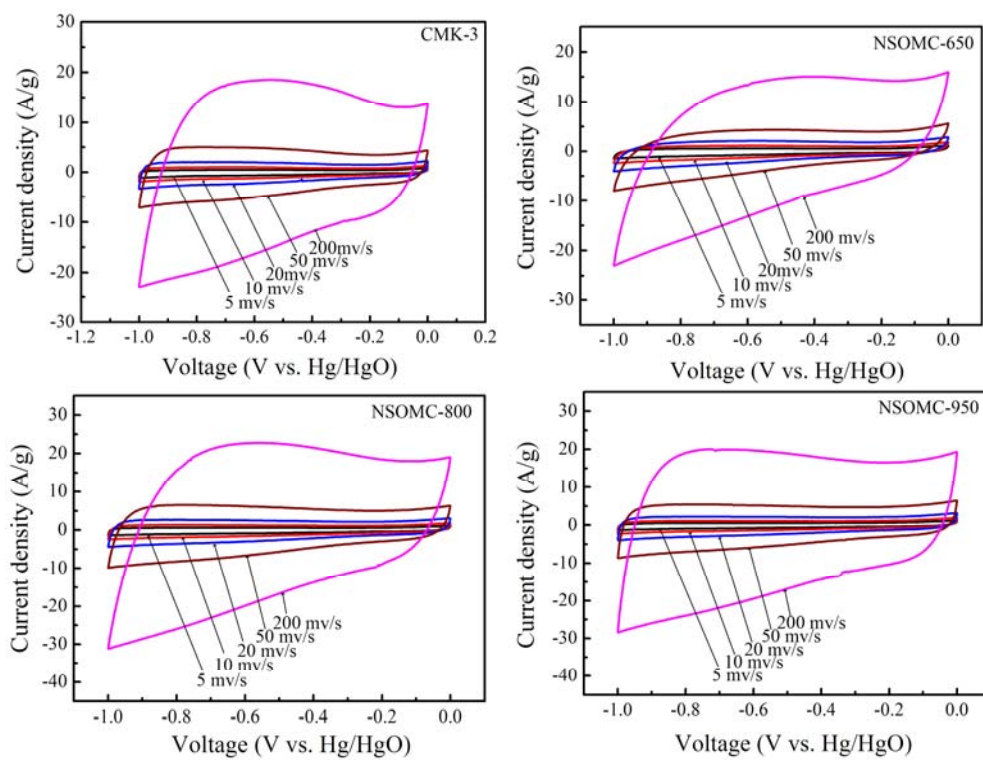


Figure S2. The CV curves of CMK-3 and NSOMC materials at different scan rates.